

#### Feature

Pass Bands: 24GHz ~ 28GHz, 28GHz ~ 32GHz, 32GHz ~ 36GHz, 36GHz ~ 40GHz; Insertion Loss in pass bands:  $\leq$ 12dB Isolation between pass bands:  $\geq$ 30dB Size: 4.4x5.4x0.1mm

## Description

This device is a FET switch filter bank MMIC based on GaAs processing. Adopt +5V/0V logic control, switching time is less than 30ns typ. It has low loss, excellent isolation, and high integration.

The metallization processing of thru-holes on the plate ensures good grounding. Extra grounding measures aren't required, which is easy for application. The back metallization is suitable for eutectic sintering or conductive adhesive sticking processes.

### **Absolute Rating**

Control Voltage	-1V~+5V
Input Power	27dBm
Storage Temperature	-65~+150°C
Operating Temperature	-55~+125℃

## **Electrical Specifications 1** ( $T_A$ =+25°C)

Spec.	Pass band 1	Pass band 2	Unit
Freq. Range	24~28	28~32	GHz
Insertion Loss	≤9.3	≤9.5	dB
Rejection	≥20@21.57GHz&30.2GHz	≥20@25.2GHz&34.2GHz	dBc
	≥30@21GHz&30.6GHz	≥30@24.4GHz&34.6GHz	dBc
VSWR	≤2		_

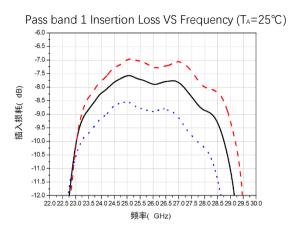
#### **Electrical Specifications 2** (T<sub>A</sub>=+25°C)

Spec.	Pass band 3	Pass band 4	Unit
Freq. Range	32~36	36~40	GHz
Insertion Loss	≤12	≤10.5	dB
Deiestier	≥20@30GHz&38.4GHz	≥20@33GHz&42.5GHz	dBc
Rejection	≥30@29GHz&39GHz	≥30@32.5GHz&43.1GHz	dBc
VSWR	≤2		

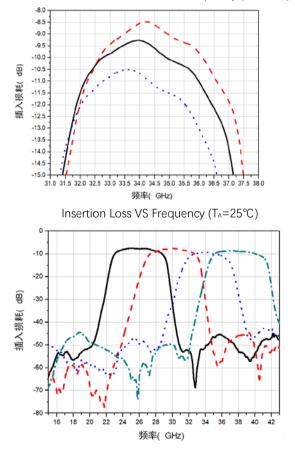
S2P file name: BWSBF-24\_40-4.s2p



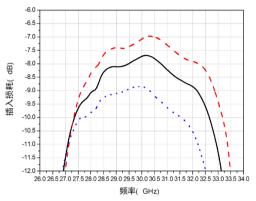
## **Typical Test Curves**



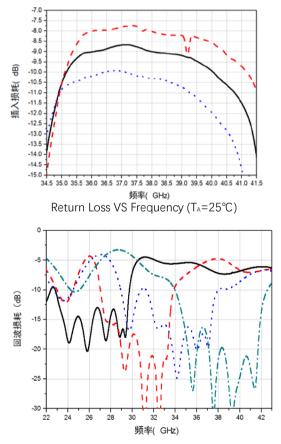
Pass band 3 Insertion Loss VS Frequency (T<sub>A</sub>=25°C)



Pass band 2 Insertion Loss VS Frequency (T<sub>A</sub>=25°C)

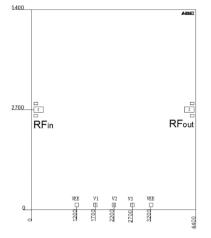


Pass band 4 Insertion Loss VS Frequency ( $T_A=25^{\circ}C$ )





## **Mechanical Specification**



# Truth Table

Control Voltage (VEE=-5V)		Dece bando		
V1	V2	V3	Pass bands	
0	0	0	24GHz~28GHz	
1	0	1	28GHz~32GHz	
0	0	1	32GHz~36GHz	
1	1	1	36GHz~40GHz	
Status: Low (0) 0V; High (1) +5V				

#### **PINS Definitions**

Pin No.	Symbol	Description
1, 2	RFin, RFout	RF Input, RF Output
3, 4, 5	V1, V2, V3	Control ports

### **Recommended Assembly Diagrams**



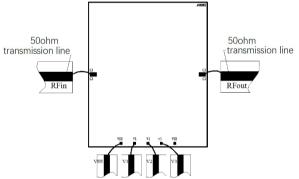
1. Dimensions are um. Tolerance: ±0.05mm

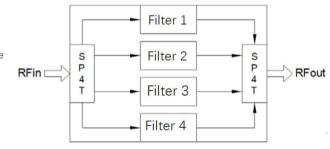
2. Die thickness is 0.1mm

3. Typical bond pad is 100um  $\star 100$ um, which is 50um away from chip edge.

4. The bottom of the device is gold plated, should be grounded.

### **Functional Diagram**





### **Application Notes:**

1. The chip is back-metallized and can be die-mounted with AuSn eutectic preforms or with electrically conductive epoxy.

2. The die should be assembled on carriers like Kovar or Mu-Cu which have same Coefficient of thermal expansion. ( $5.8 \times 10-6$ /) with GaAs.

- 3. Recommend using  $\Phi$ 25um Au wire for bonding, whose length is around 200um.
- 4. Sinter by AuSn (80/20), which doesn't exceed 300°C within 30 seconds max.
- 4. Handle the chips in a clean environment. DO NOT attempt to clean the chip using liquid cleaning systems.
- 5. Handle the chip along the edges with a vacuum collet or with a sharp pair of bent tweezers.
- 6. The device is sensitive to ESD. ESD protection is required during storage and usage.
- 7. If you have any questions, please contact us.